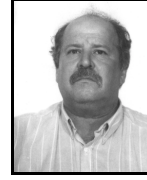
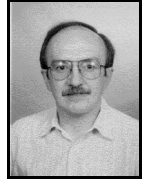




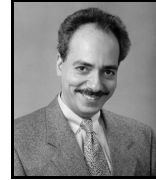
DEFECT ORIENTED TEST
Joan Figueras
 UPC, ES



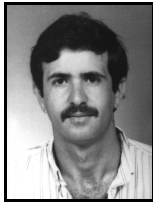
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